

Sub F⁹
✓ 132. (New) The imaging device according to claim 122 wherein each said photogate and said nitrogen containing insulating layer are only partially disposed over said gate stack.

133. (New) The imaging device according to claim 123 wherein each said photogate and said nitrogen containing insulating layer are only partially disposed over said gate stack.

Sub I¹
Sub E²
✓ 134. (New) The imaging device according to claim 124 wherein each said photogate and said nitrogen containing insulating layer are only partially disposed over said gate stack.

135. (New) The imaging device according to claim 120, wherein said gate stack is comprised of a transfer gate stack and a reset gate stack.

136. (New) The imaging device according to claim 121, wherein said gate stack is comprised of a transfer gate stack and a reset gate stack.

137. (New) The imaging device according to claim 122, wherein said gate stack is comprised of a transfer gate stack and a reset gate stack.

138. (New) The imaging device according to claim 123, wherein said gate stack is comprised of a transfer gate stack and a reset gate stack.

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139. (New) The imaging device according to claim 124, wherein said gate stack is comprised of a transfer gate stack and a reset gate stack.

Sub F¹¹
✓ 140. (New) The imaging device according to claim 135, wherein said nitrogen containing insulating layer is disposed only over either said transfer gate stack or said reset gate stack.

141. (New) The imaging device according to claim 136, wherein said nitrogen containing insulating layer is disposed only over either said transfer gate stack or said reset gate stack.

142. (New) The imaging device according to claim 137, wherein said nitrogen containing insulating layer is disposed only over either said transfer gate stack or said reset gate stack.

143. (New) The imaging device according to claim 138, wherein said nitrogen containing insulating layer is disposed only over either said transfer gate stack or said reset gate stack.

144. (New) The imaging device according to claim 139, wherein said nitrogen containing insulating layer is disposed only over either said transfer gate stack or said reset gate stack.

145. (New) The imaging device according to claim 135, wherein said nitrogen containing insulating layer is deposited over said transfer gate stack and said reset gate stack.

146. (New) The imaging device according to claim 136, wherein said nitrogen containing insulating layer is disposed only over either said transfer gate stack or said reset gate stack.

147. (New) The imaging device according to claim 137, wherein said nitrogen containing insulating layer is disposed only over either said transfer gate stack or said reset gate stack.

148. (New) The imaging device according to claim 138, wherein said nitrogen containing insulating layer is disposed only over either said transfer gate stack or said reset gate stack.

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